

# Analysis of the Leakage Current of GaInP/AlGaInP High Power Lasers with a self-consistent Simulation Model

J. M.G. Tijero<sup>1</sup>, H. Odriozola<sup>1</sup>, I. Esquivias<sup>1</sup>, A. Martín-Mínguez<sup>1</sup>, P. Brick<sup>2</sup>, M. Reufer<sup>2</sup>, M. Bou Sanayeh<sup>2</sup>, A. Gomez-Iglesias<sup>2</sup>, and N. Linder<sup>2</sup>

(1) E. T. S. I. Telecomunicación, Univ. Politécnica de Madrid. Madrid, Spain.

(2) Osram Opto Semiconductors, Regensburg, Germany.

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- Introduction and goals
- Experimental characterisation
- Simulation model
- Analysis of leakage current: sensitivity to model parameters
- Conclusions



# High Power Red Lasers

## Main applications:

- ❑ Photodynamic Therapy
- ❑ Fluorescence Imaging of Cancer
- ❑ Laser Display Technology
- ❑ Pumping of Solid State Lasers

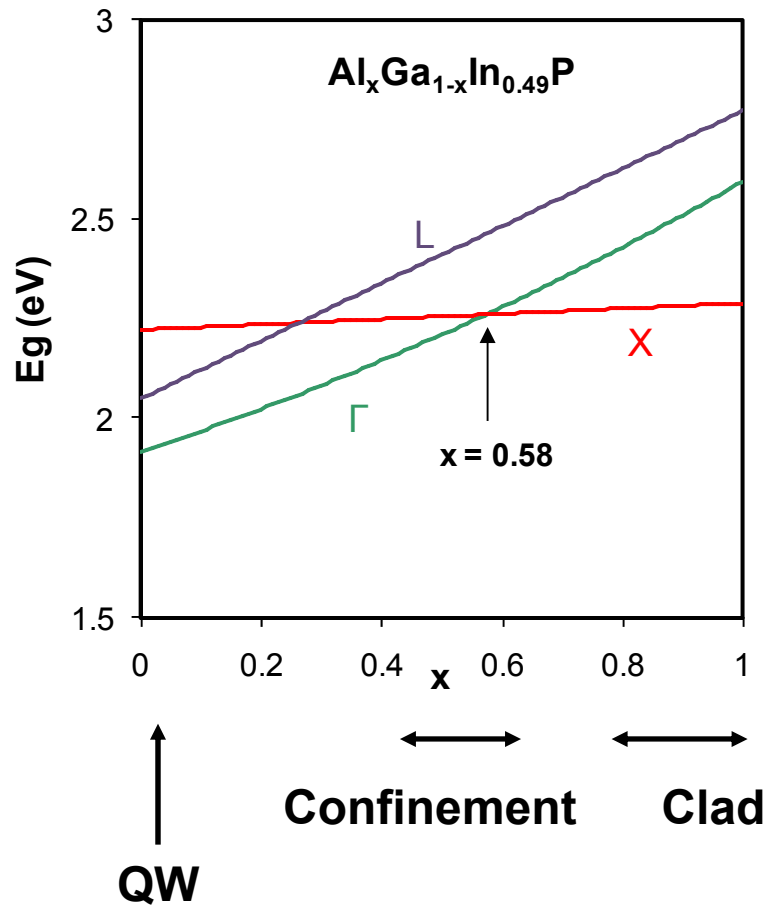
## Main problems:

- ❑ High dependence of threshold current with temperature
- ❑ Decrease of slope efficiency with temperature
- ❑ Catastrophical Optical Damage
- ❑ Gradual degradation

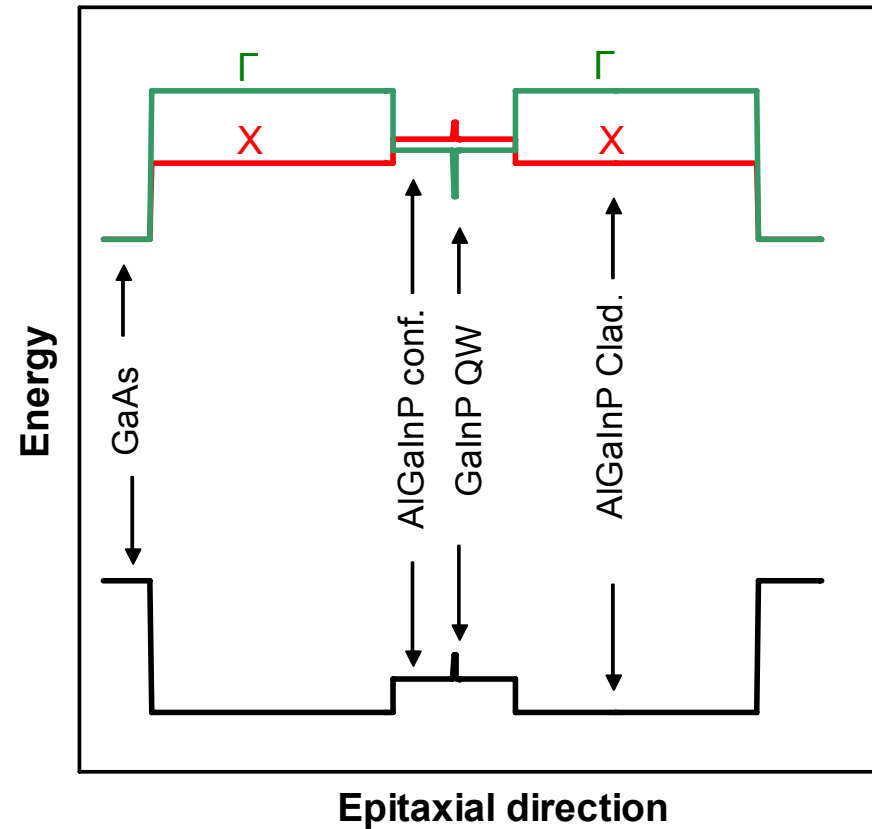


# GaInP/AlGaInP Red Lasers

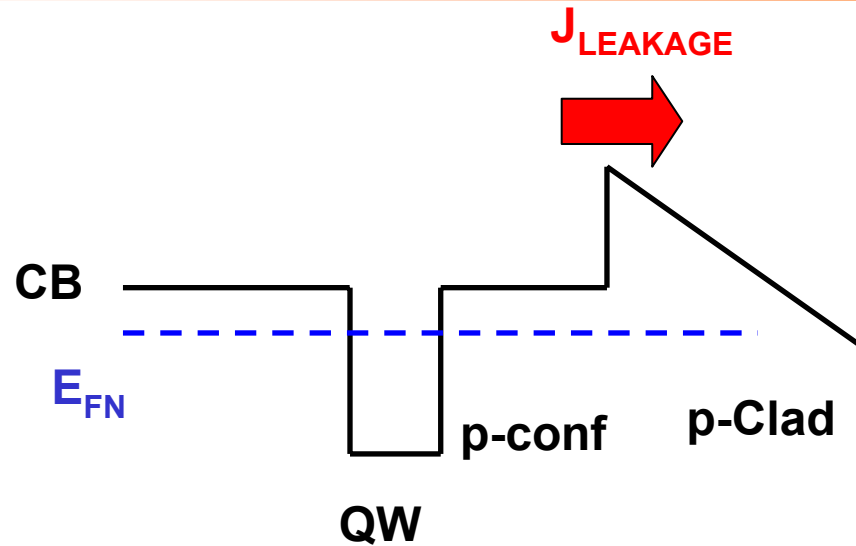
Band-gap vs. composition



Schematic band alignment



# Leakage Current in Red Lasers



## Analytical Model

$$J_{LEAK} = J_{DRIFT} + J_{DIFFUSION}$$

Leakage current depends on:  
band-offset, mobilities, carrier lifetime....



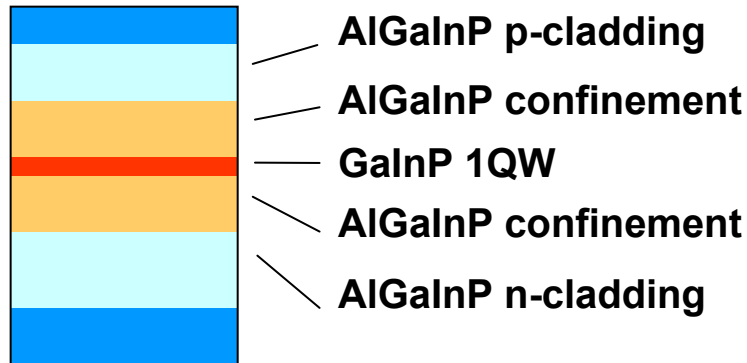
- ❑ Analyze leakage current with a self-consistent laser model
- ❑ Evaluate the sensitivity of the results to the values of some material parameters
- ❑ Evaluate the effect of some design parameters: p-doping



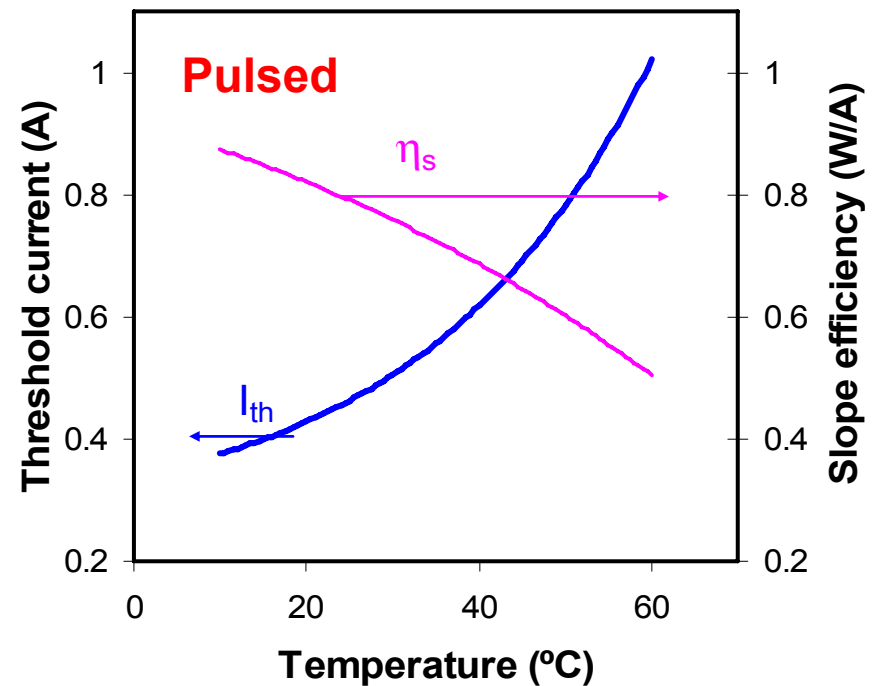
# Laser Devices and Experimental characterisation

Broad Area Lasers  
100  $\mu\text{m}$  x 1.2 mm

Epitaxial design



Wavelength: 635 nm



# Self-consistent laser model

Main features:

- ❑ Complete semiconductor equations: Poisson + continuity electrons + continuity holes
- ❑ QW carrier capture/escape processes
- ❑ Gain calculations using parabolic fitting of VB structure (calculated by **k.p** band mixing model)
- ❑  $\Gamma$  and X valleys in the CB

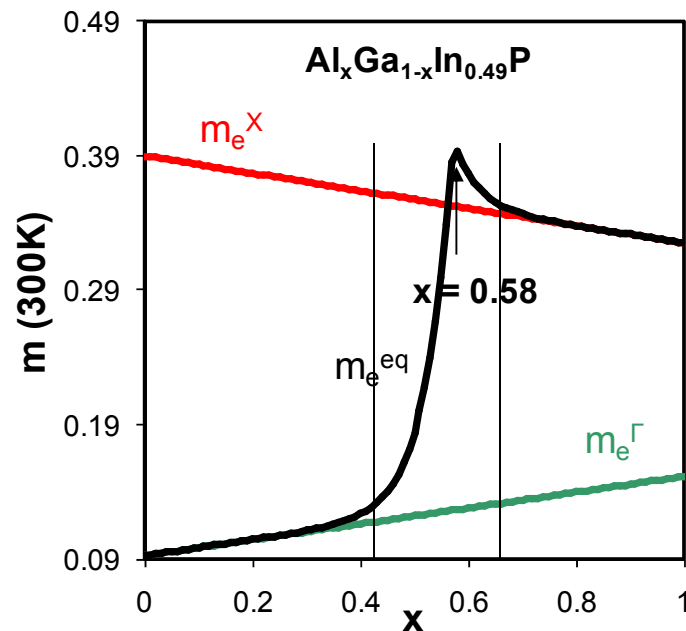




# Model for multiple valleys in CB

- Assumption: thermal equilibrium between electrons in different valleys
- Single CB minimum with equivalent effective mass and mobility
- $m_e^{eq}$  and  $\mu_e^{eq}$  are calculated analytically
 
$$m_e^{eq} = f_m(m_e^X, m_e^\Gamma, E_C^X - E_C^\Gamma, T)$$

$$\mu_n^{eq} = f_\mu(\mu_n^X, \mu_n^\Gamma, E_C^X - E_C^\Gamma, T)$$



Equivalent effective electron mass

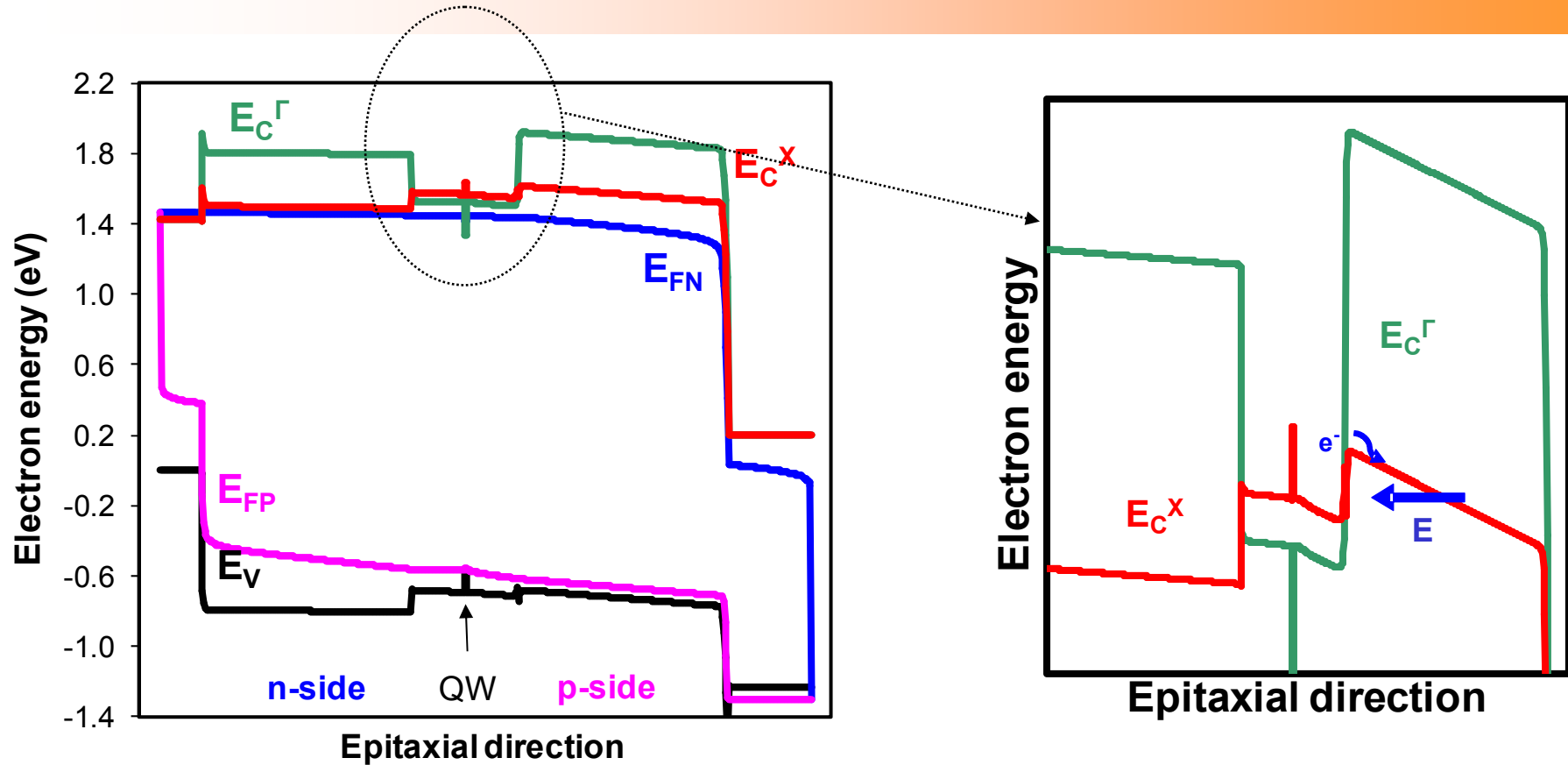


# Main model parameters affecting leakage

- **Electron/ hole mobilities**
- **Electron/ hole capture times**
- Band line-ups
- $\Gamma$  and X valleys effective masses
- **SRH recombination parameters**: trap density, trap energy, trap carrier capture section



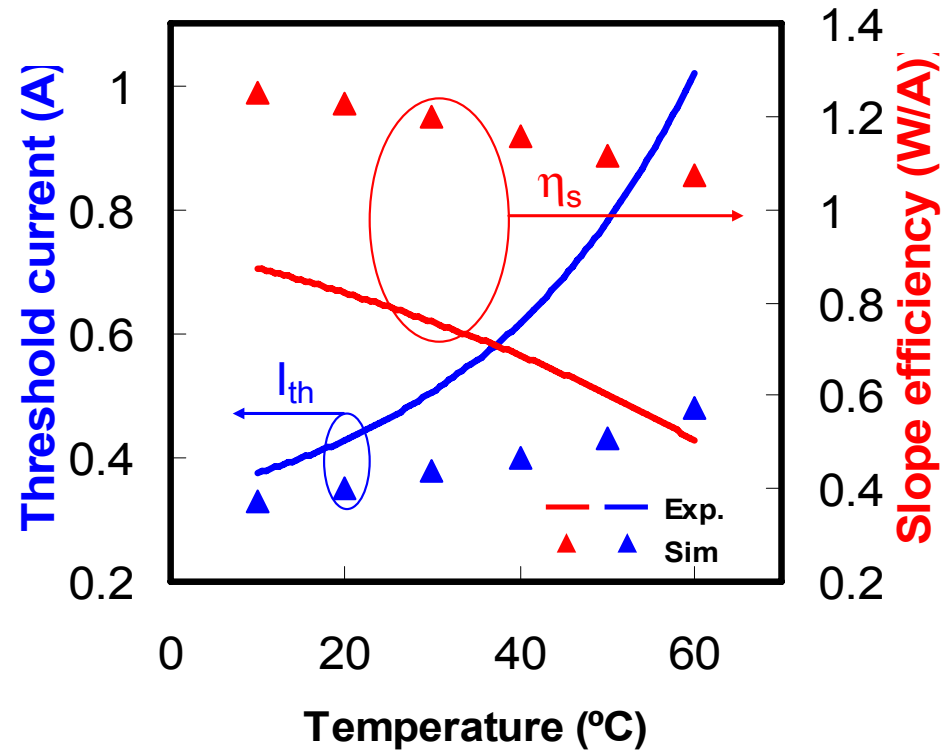
# Band profiles under bias



$T = 20\text{ }^{\circ}\text{C}; I = 2\text{ A}$



# No SRH recombination

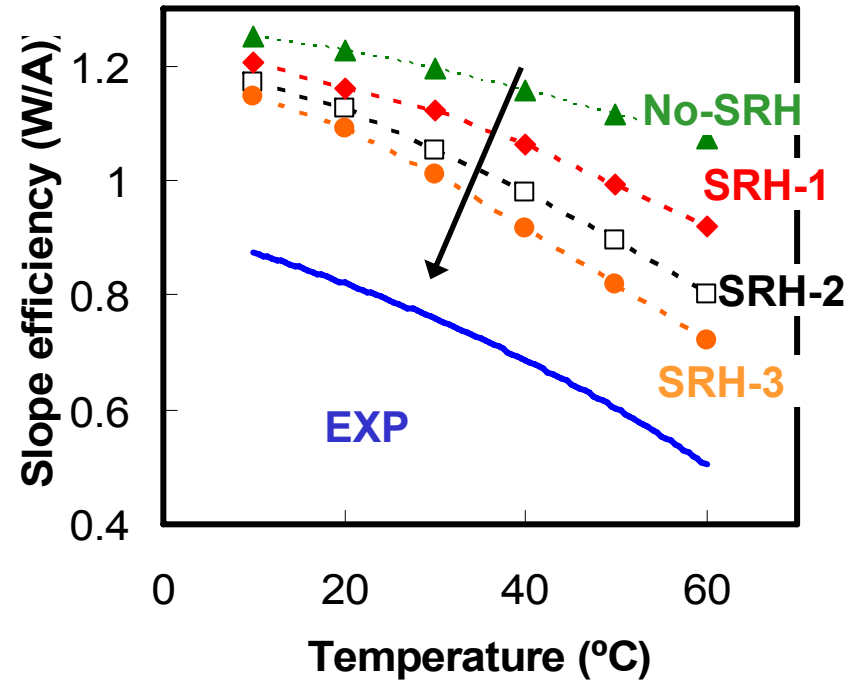
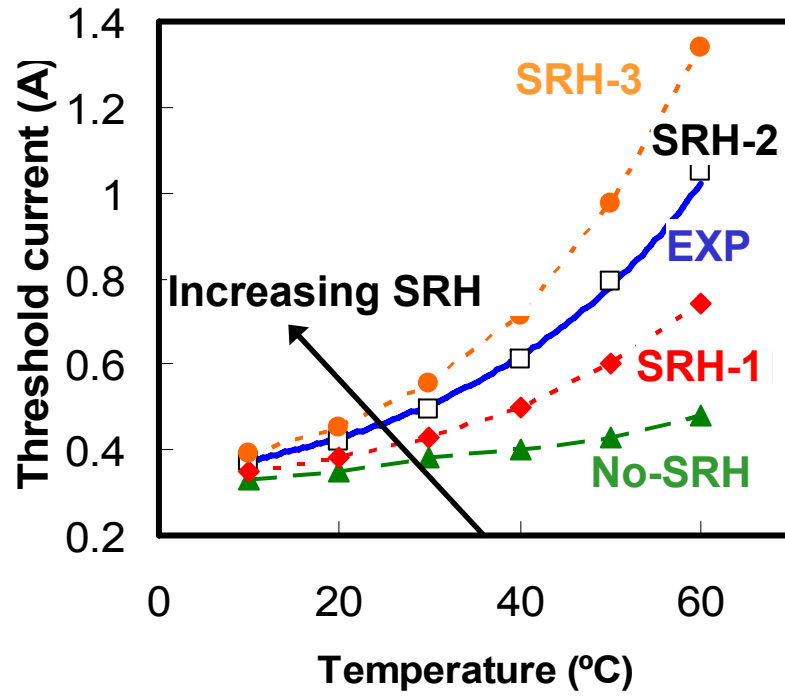


- ✓ Low  $I_{th}$ ; weak temperature dependence
- ✓ High  $\eta_s$ ; weak temperature dependence





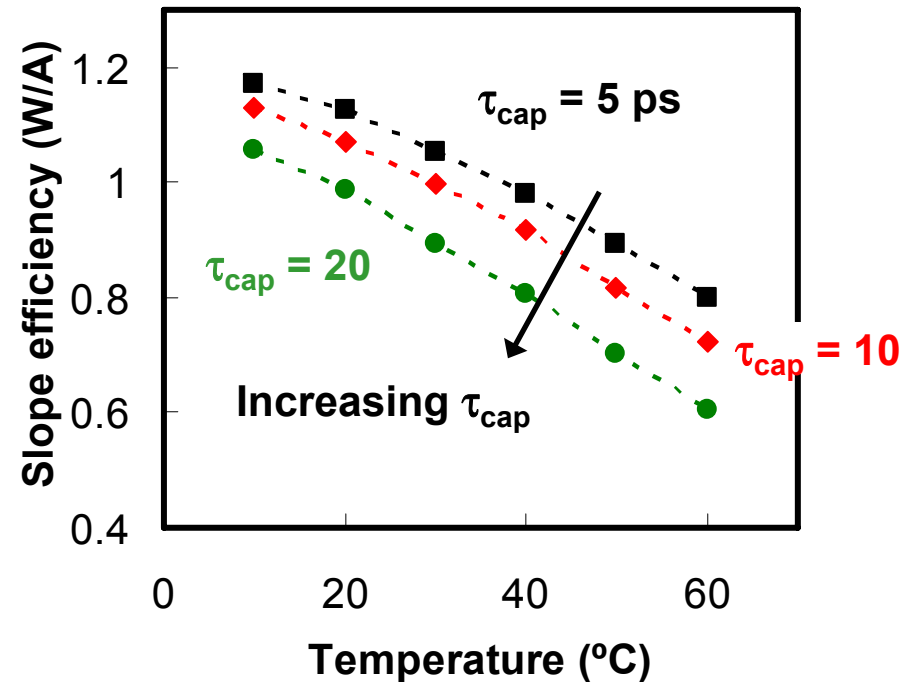
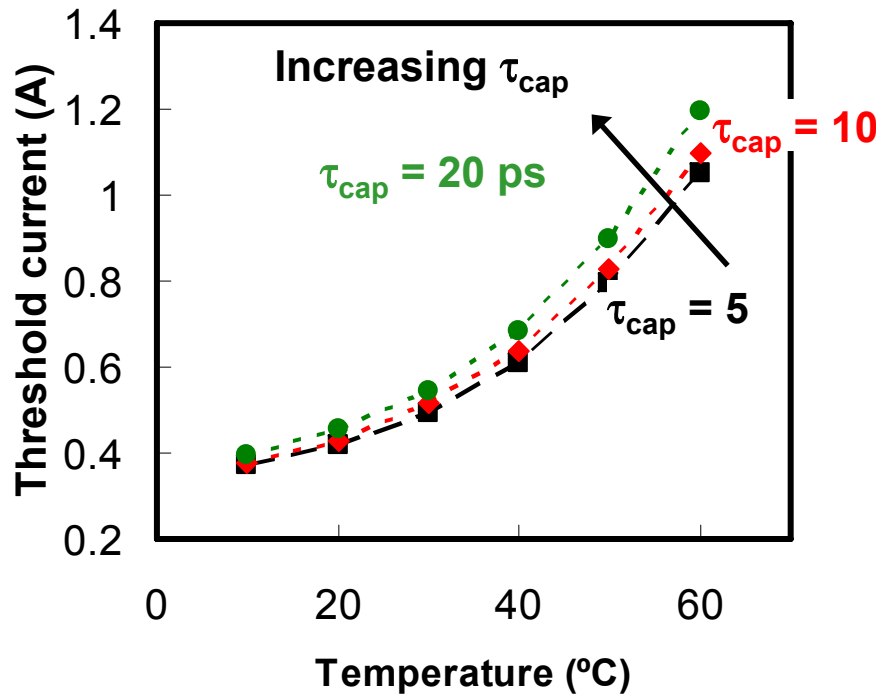
# Role of SRH recombination



	Traps in p-conf	Traps in p-clad
SRH-1	$1 \cdot 10^{17} \text{ cm}^{-3}$	$0.5 \cdot 10^{16} \text{ cm}^{-3}$
SRH-2	$3 \cdot 10^{17} \text{ cm}^{-3}$	$1 \cdot 10^{16} \text{ cm}^{-3}$
SRH-3	$5 \cdot 10^{17} \text{ cm}^{-3}$	$1.5 \cdot 10^{16} \text{ cm}^{-3}$



# Role of electron capture time



$\tau_{cap} \uparrow \longrightarrow I_{leakage} \uparrow$

(Increasing electron density in confinement layers)



# Role of carrier mobility in p-clad

$\mu_p$  (majority)  $\uparrow$   $\longrightarrow$   $I_{\text{leakage}}$  (drift)  $\downarrow$

Lower Electric field ( $J_p = q\mu_p E$ )

$\mu_n$  (minority)  $\uparrow$   $\longrightarrow$   $I_{\text{leakage}}$  (diffusion)  $\uparrow$

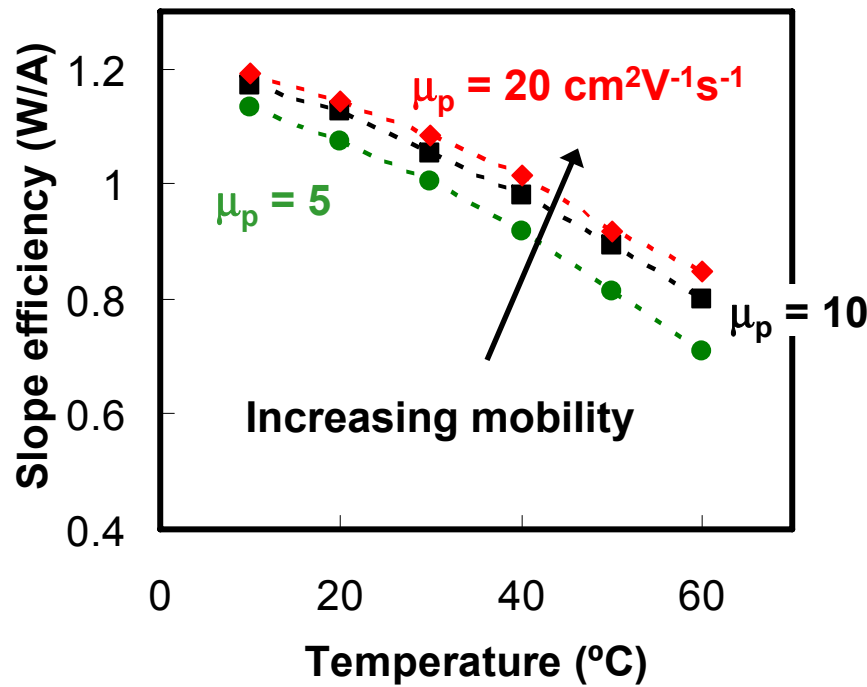
Higher diffusion coefficient ( $J_{n(\text{dif})} = \mu_n kT dn/dx$ )



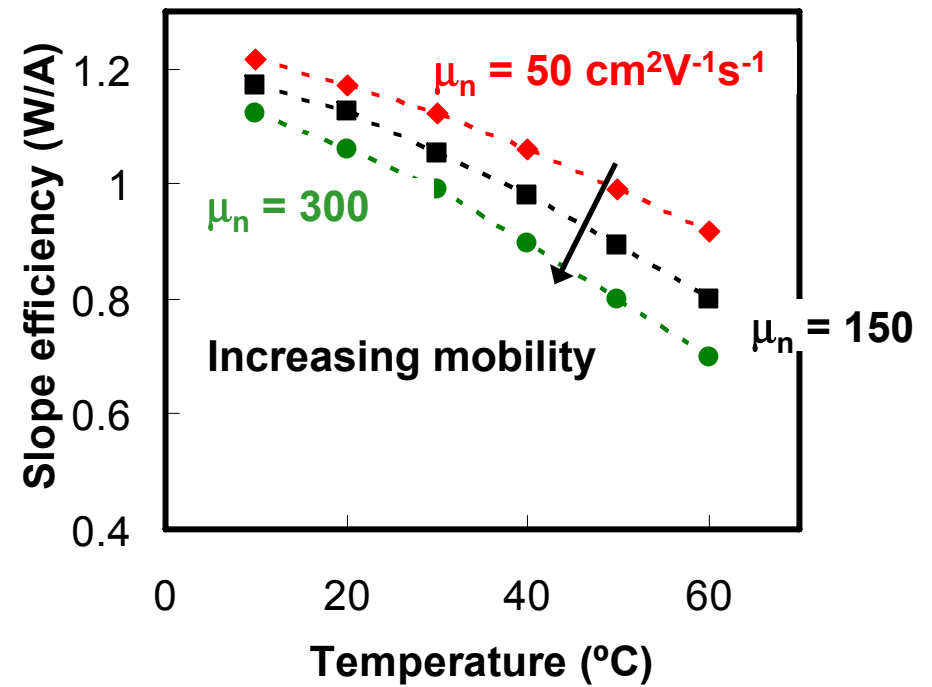


# Role of carrier mobility in p-clad

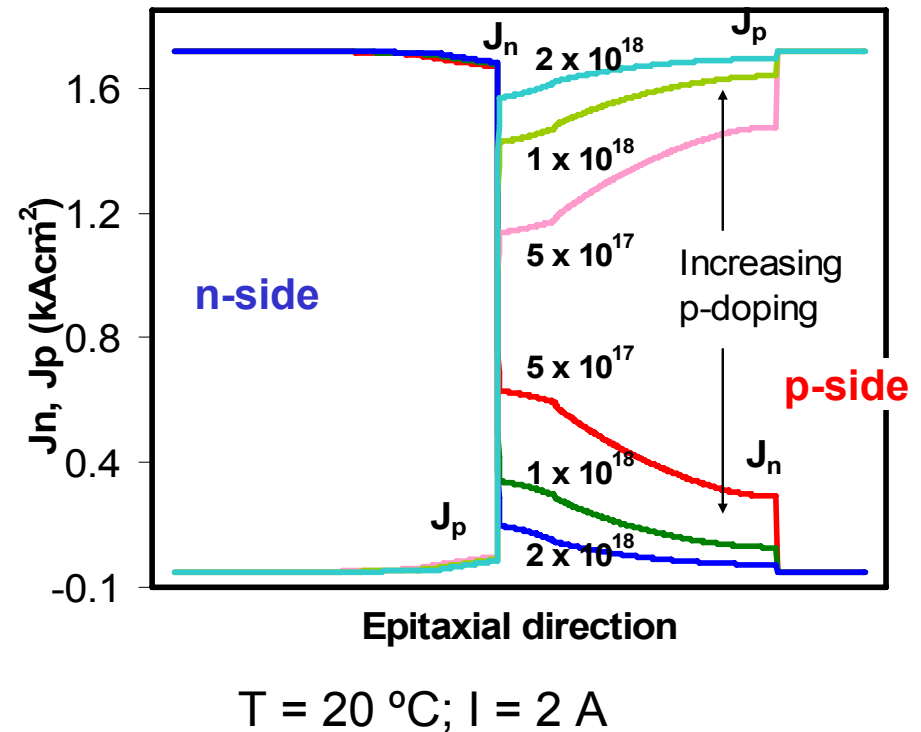
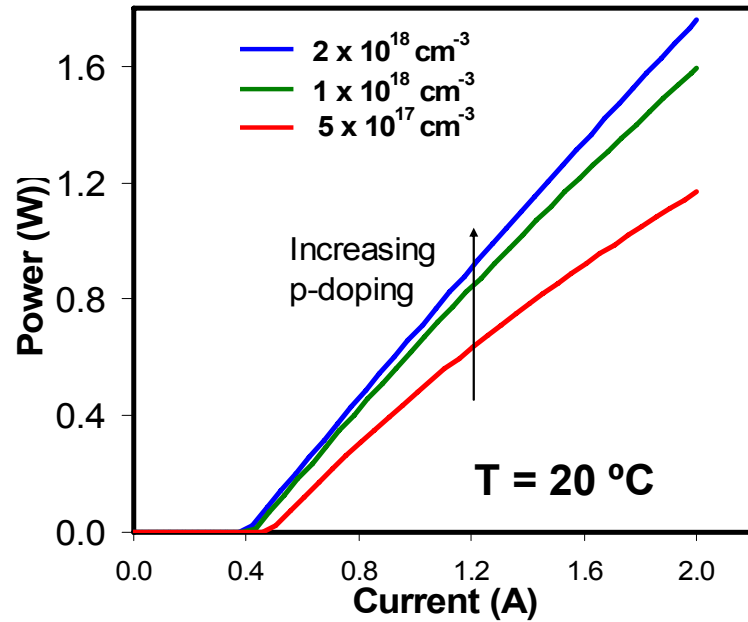
$\mu_p$  (majority)



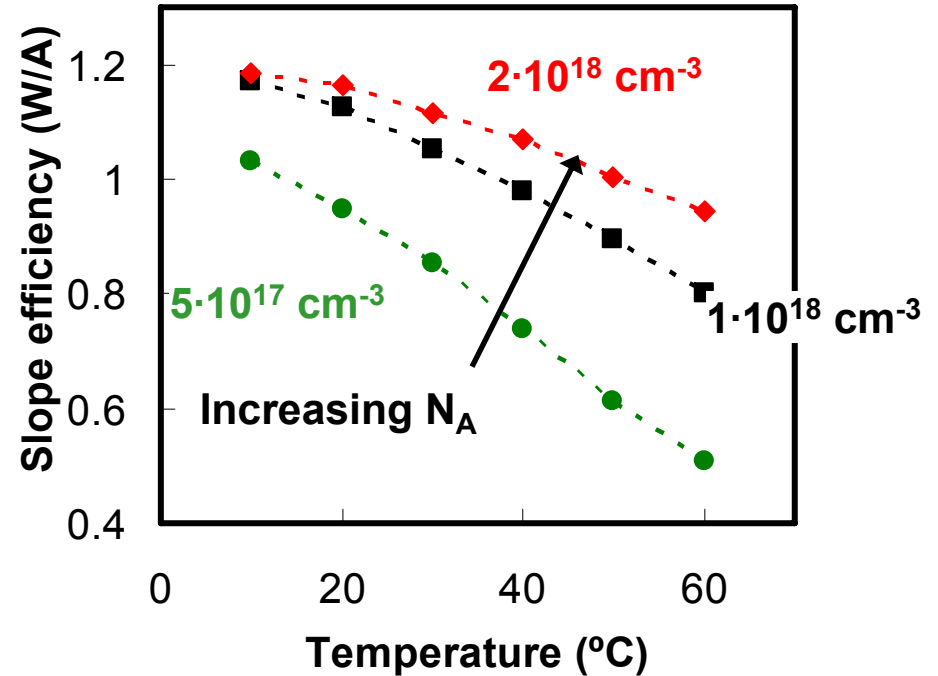
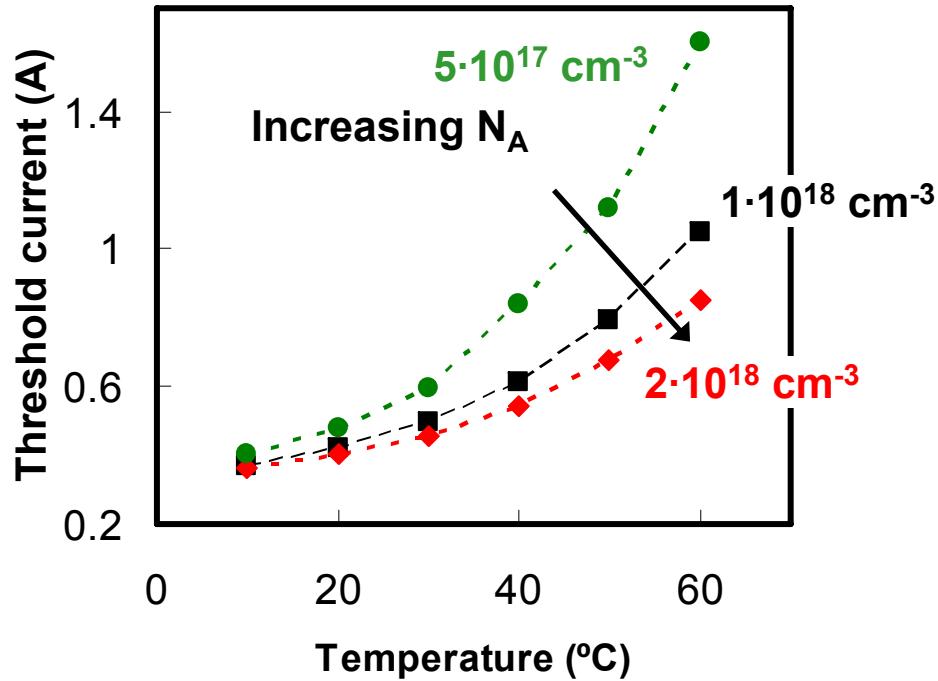
$\mu_n$  (minority)



# Role of doping in p-cladding



# Role of doping in p-cladding



✓ Increasing p-doping reduces drift leakage

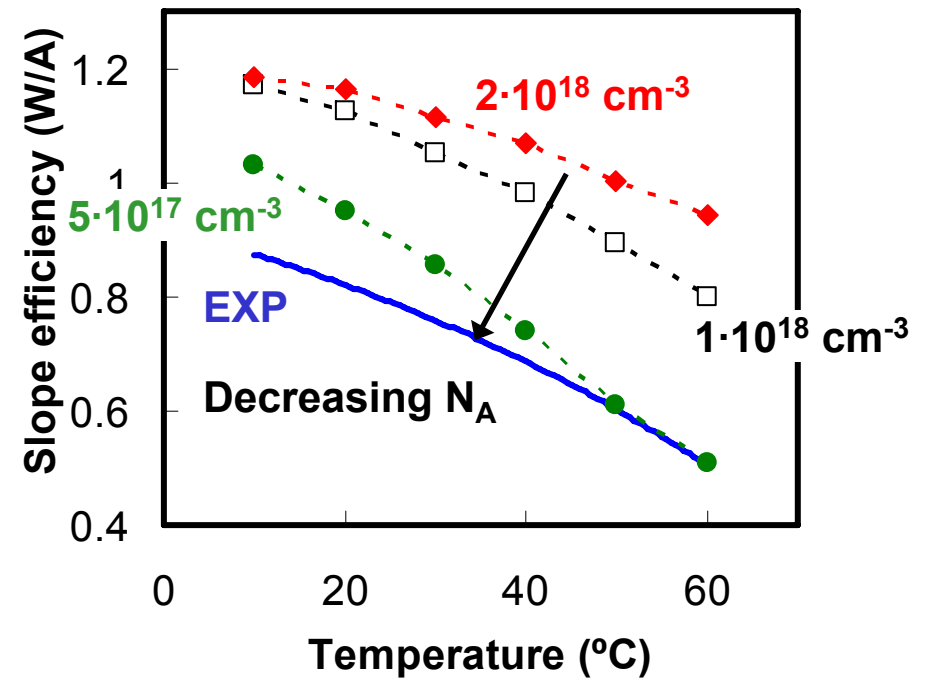
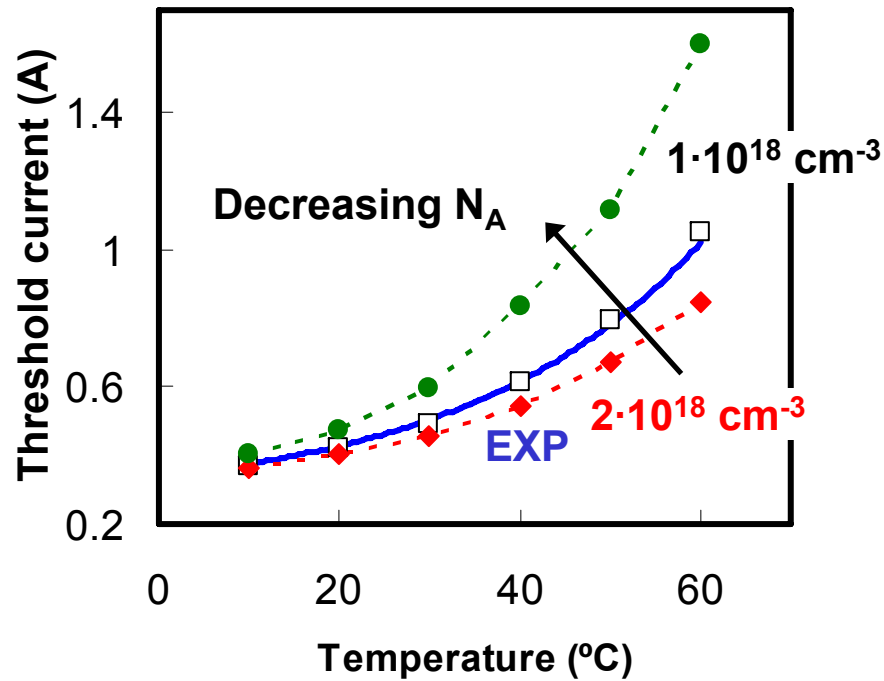


# Conclusions

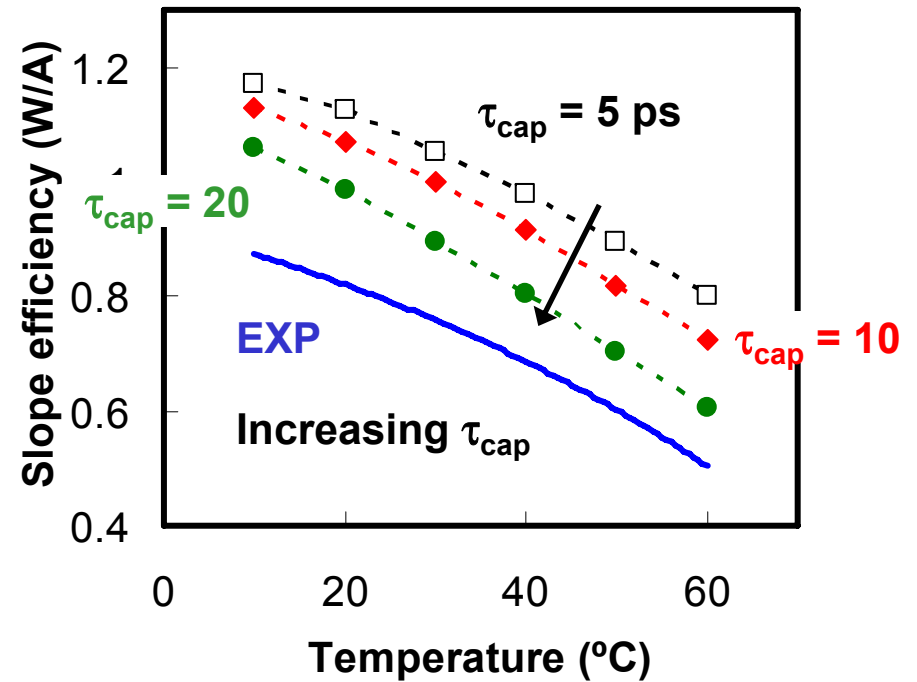
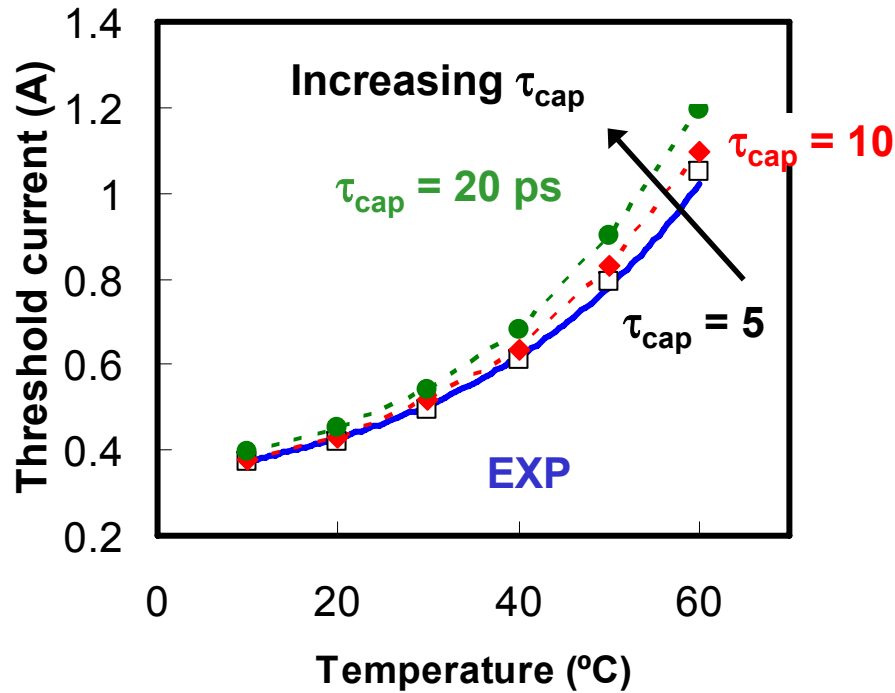
- ✓ Self-consistent model predicts leakage current over p-cladding
- ✓ Leakage current is very sensitive to model parameters
- ✓ Need to determine basic material parameters to optimize red lasers
- ✓ Simulation emphasizes the Important role of increasing p-doping level.



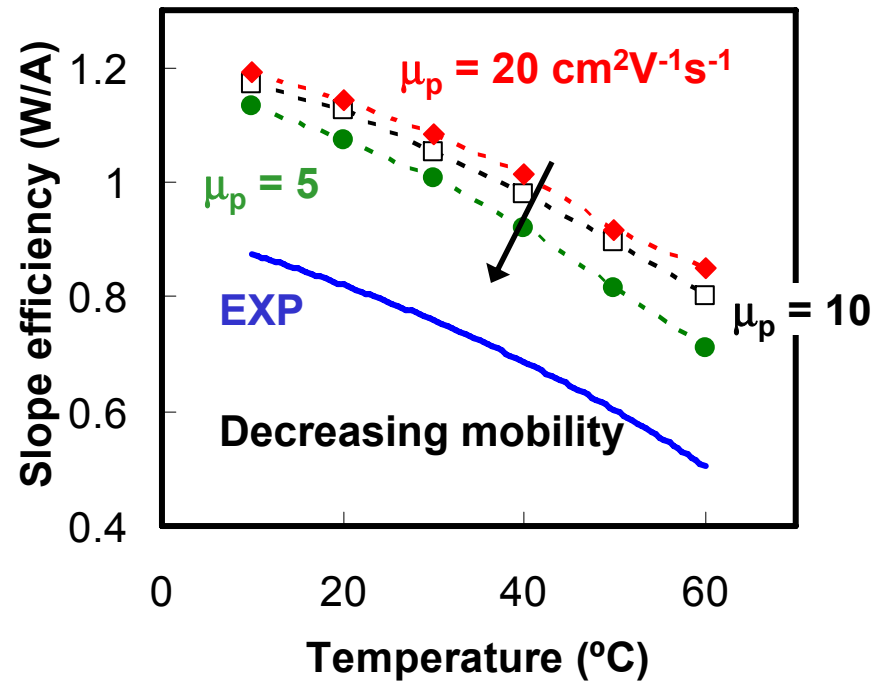
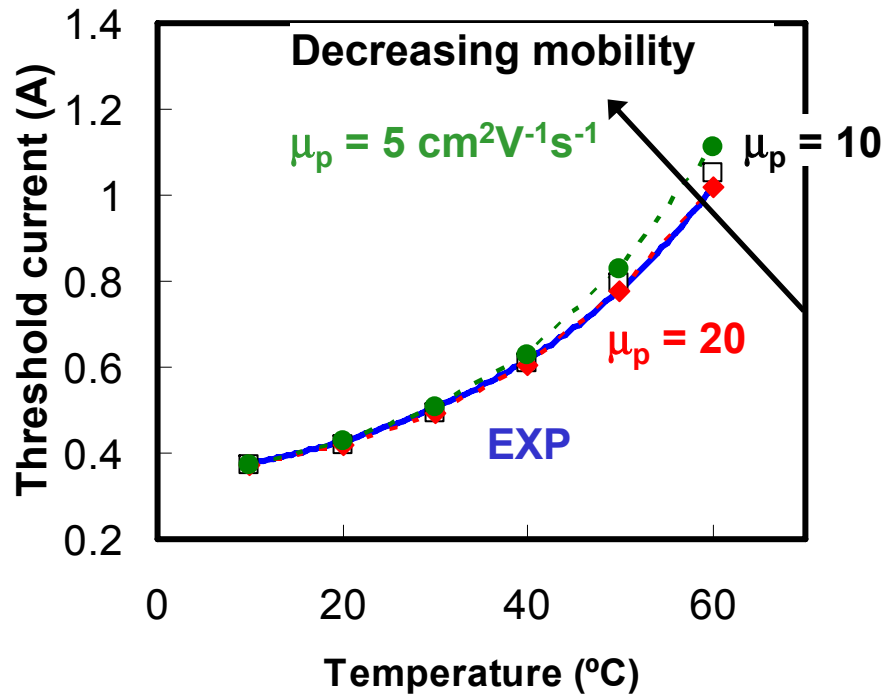
# Role of doping in p-cladding



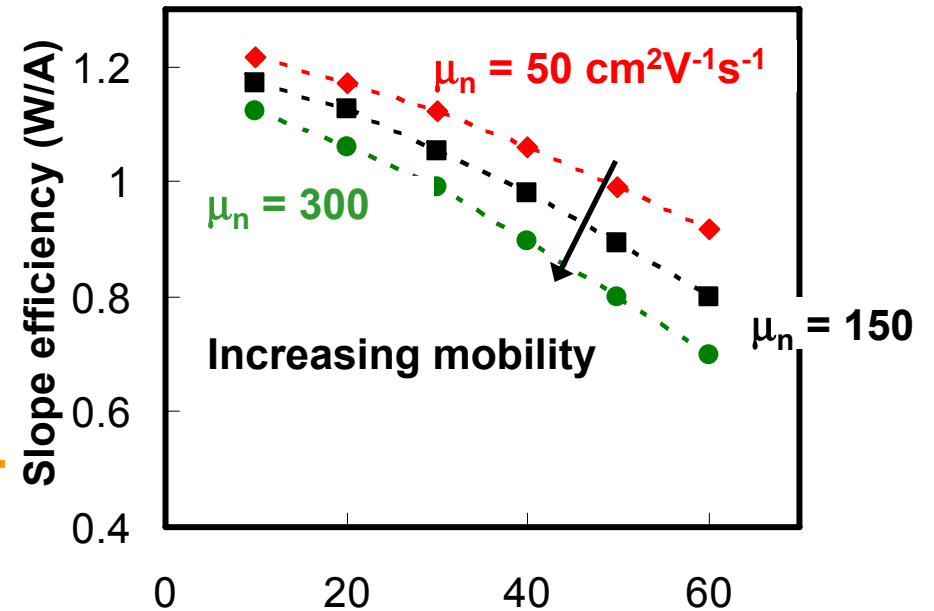
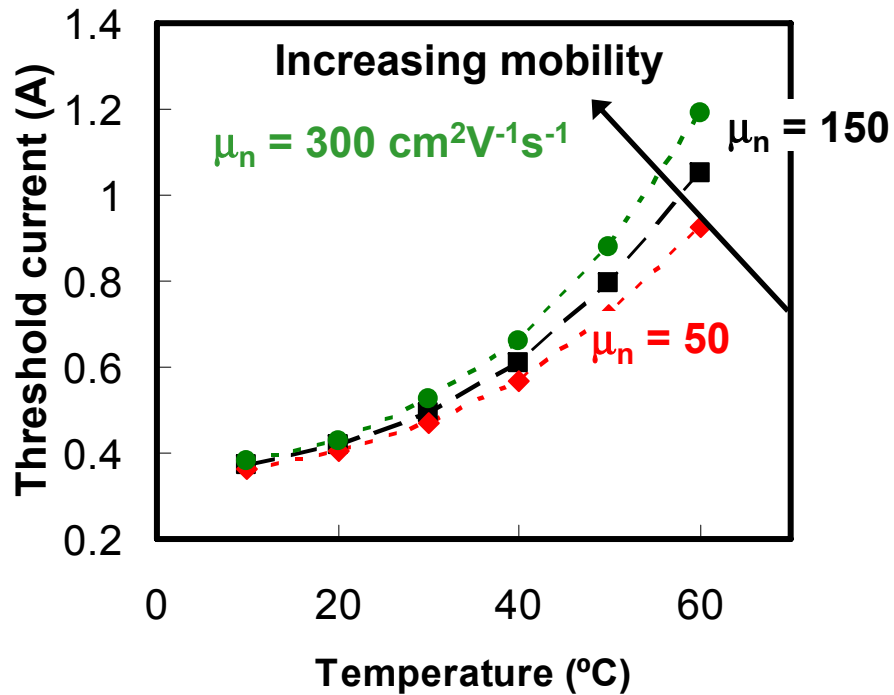
# Role of electron capture time



# Role of hole mobility in p-clad

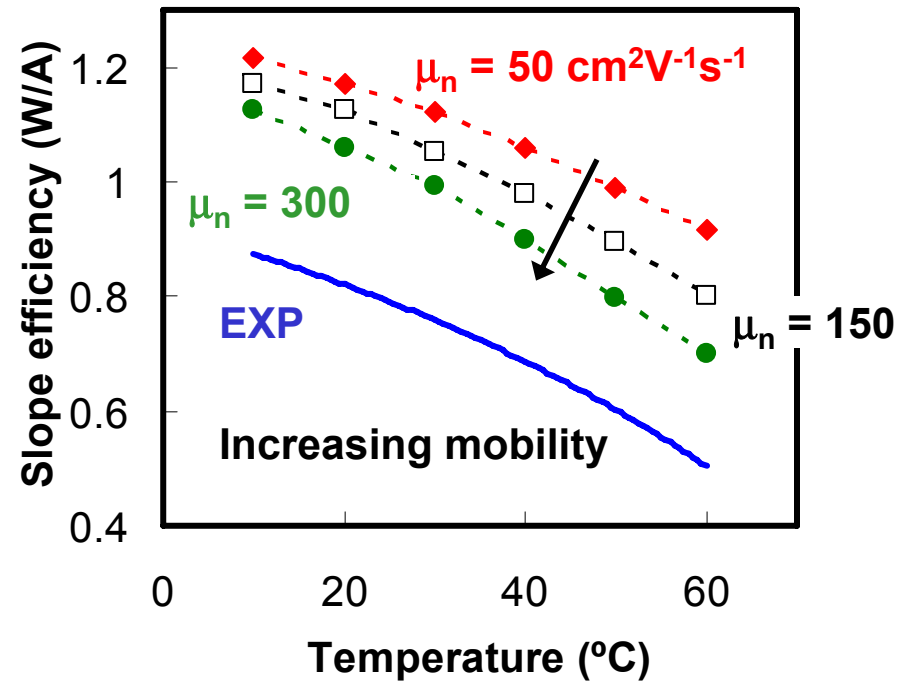
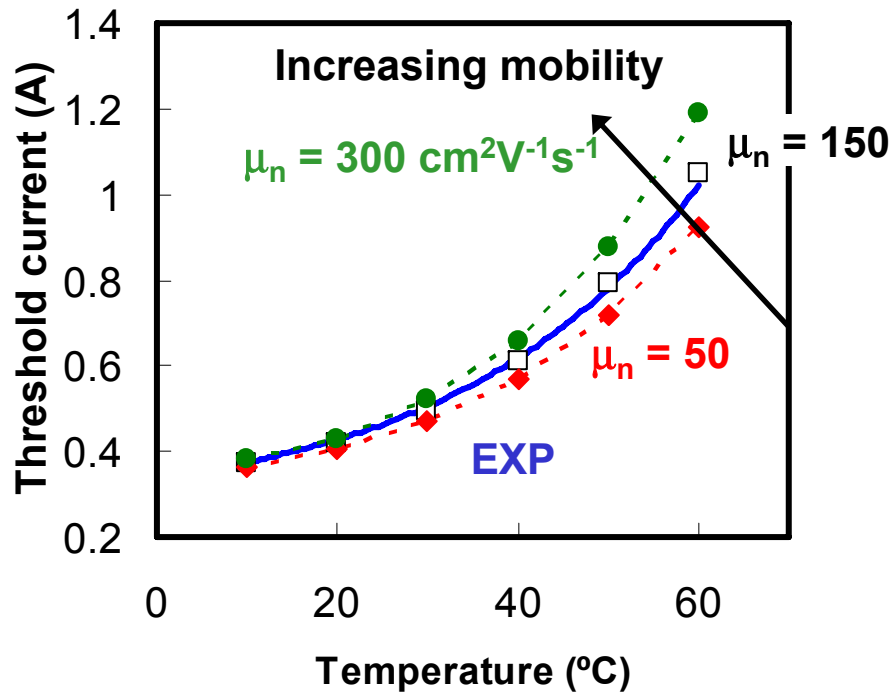


# Role of electron mobility in p-clad





# Role of electron mobility in p-clad



# Role of hole mobility in p-clad

